

PHD108NQ03LT

N-channel TrenchMOS logic level FET

Rev. 04 — 5 June 2009

Product data sheet

1. Product profile

1.1 General description

Logic level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product is designed and qualified for use in computing, communications, consumer and industrial applications only.

1.2 Features and benefits

- Low conduction losses due to low on-state resistance
- Simple gate drive required due to low gate charge
- Suitable for logic level gate drive sources

1.3 Applications

- DC-to-DC convertors
- Switched-mode power supplies

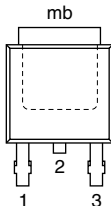
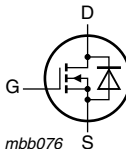
1.4 Quick reference data

Table 1. Quick reference

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V_{DS}	drain-source voltage	$T_j \geq 25\text{ °C}$; $T_j \leq 175\text{ °C}$	-	-	25	V
I_D	drain current	$T_{mb} = 25\text{ °C}$; $V_{GS} = 5\text{ V}$; see Figure 1 ; see Figure 3	-	-	75	A
P_{tot}	total power dissipation	$T_{mb} = 25\text{ °C}$; see Figure 2	-	-	187	W
Avalanche ruggedness						
$E_{DS(AL)S}$	non-repetitive drain-source avalanche energy	$V_{GS} = 10\text{ V}$; $T_{j(init)} = 25\text{ °C}$; $I_D = 43\text{ A}$; $V_{sup} \leq 25\text{ V}$; unclamped; $t_p = 0.25\text{ ms}$; $R_{GS} = 50\text{ }\Omega$	-	-	180	mJ
Dynamic characteristics						
Q_{GD}	gate-drain charge	$V_{GS} = 4.5\text{ V}$; $I_D = 25\text{ A}$; $V_{DS} = 12\text{ V}$; $T_j = 25\text{ °C}$; see Figure 12 ; see Figure 13	-	5.6	-	nC
Static characteristics						
$R_{DS(on)}$	drain-source on-state resistance	$V_{GS} = 10\text{ V}$; $I_D = 25\text{ A}$; $T_j = 25\text{ °C}$; see Figure 10 ; see Figure 11	-	5.3	6	m Ω

2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		
2	D	drain		
3	S	source		
mb	D	mounting base; connected to drain		
SOT428 (SC-63; DPAK)				<i>mbb076</i>

[1] It is not possible to make a connection to pin 2.

3. Ordering information

Table 3. Ordering information

Type number	Package		Version
	Name	Description	
PHD108NQ03LT	SC-63; DPAK	plastic single-ended surface-mounted package (DPAK); 3 leads (one lead cropped)	SOT428

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

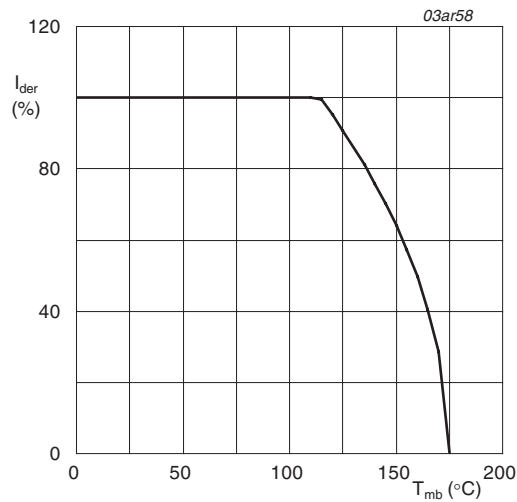
Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage	$T_j \geq 25\text{ °C}$; $T_j \leq 175\text{ °C}$	-	25	V
V_{DGR}	drain-gate voltage	$T_j \geq 25\text{ °C}$; $T_j \leq 175\text{ °C}$; $R_{GS} = 20\text{ k}\Omega$	-	25	V
V_{GS}	gate-source voltage		-20	20	V
I_D	drain current	$V_{GS} = 5\text{ V}$; $T_{mb} = 25\text{ °C}$; see Figure 1 ; see Figure 3	-	75	A
		$V_{GS} = 5\text{ V}$; $T_{mb} = 100\text{ °C}$; see Figure 1	-	75	A
I_{DM}	peak drain current	$t_p \leq 10\text{ }\mu\text{s}$; pulsed; $T_{mb} = 25\text{ °C}$; see Figure 3	-	240	A
P_{tot}	total power dissipation	$T_{mb} = 25\text{ °C}$; see Figure 2	-	187	W
T_{stg}	storage temperature		-55	175	°C
T_j	junction temperature		-55	175	°C

Source-drain diode

I_S	source current	$T_{mb} = 25\text{ °C}$	-	75	A
I_{SM}	peak source current	$t_p \leq 10\text{ }\mu\text{s}$; pulsed; $T_{mb} = 25\text{ °C}$	-	240	A

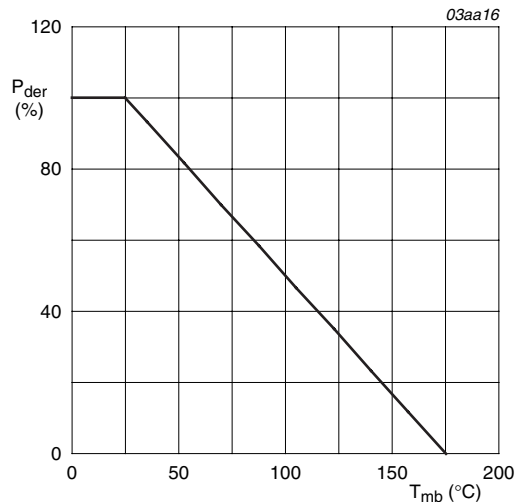
Avalanche ruggedness

$E_{DS(AL)S}$	non-repetitive drain-source avalanche energy	$V_{GS} = 10\text{ V}$; $T_{j(\text{init})} = 25\text{ °C}$; $I_D = 43\text{ A}$; $V_{sup} \leq 25\text{ V}$; unclamped; $t_p = 0.25\text{ ms}$; $R_{GS} = 50\text{ }\Omega$	-	180	mJ
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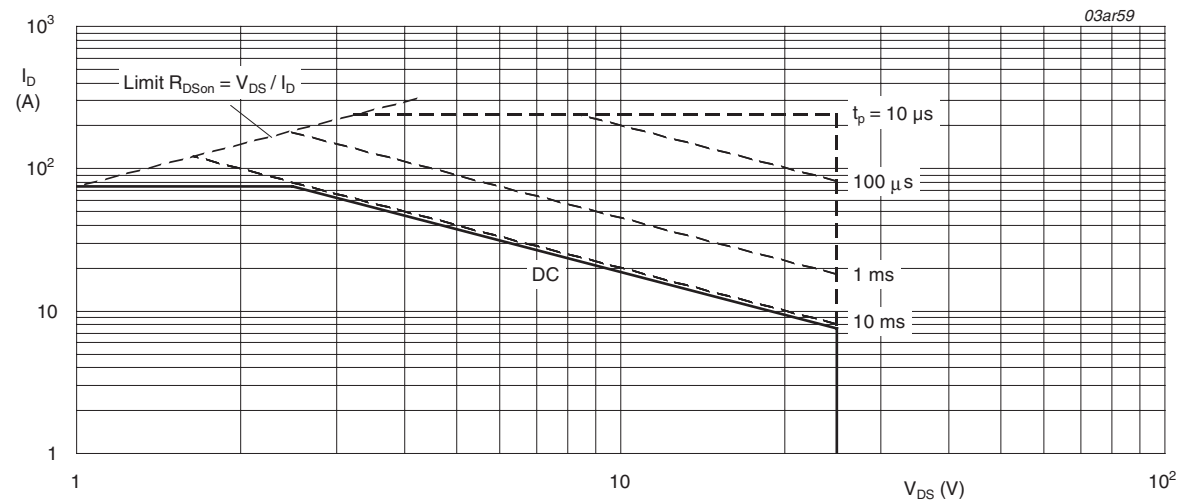
$$I_{der} = \frac{I_D}{I_{D(25^{\circ}C)}} \times 100\%$$

Fig 1. Normalized continuous drain current as a function of mounting base temperature



$$P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100\%$$

Fig 2. Normalized total power dissipation as a function of mounting base temperature



$$T_{mb} = 25^{\circ}C; I_{DM} \text{ is single pulse}; V_{GS} = 5V$$

Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	see Figure 4	-	-	0.8	K/W
$R_{th(j-a)}$	thermal resistance from junction to ambient	minimum footprint; mounted on a printed-circuit board; vertical in still air	-	75	-	K/W
		mounted on a printed-circuit board; vertical in still air; SOT404 minimum footprint	-	50	-	K/W

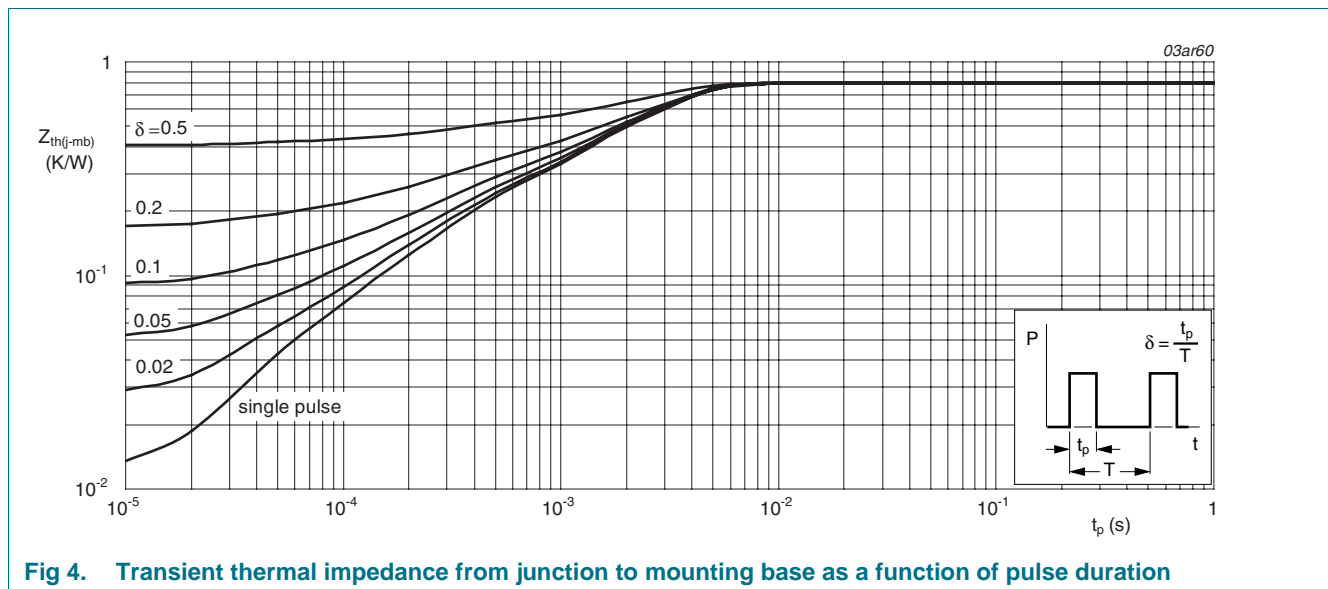


Fig 4. Transient thermal impedance from junction to mounting base as a function of pulse duration

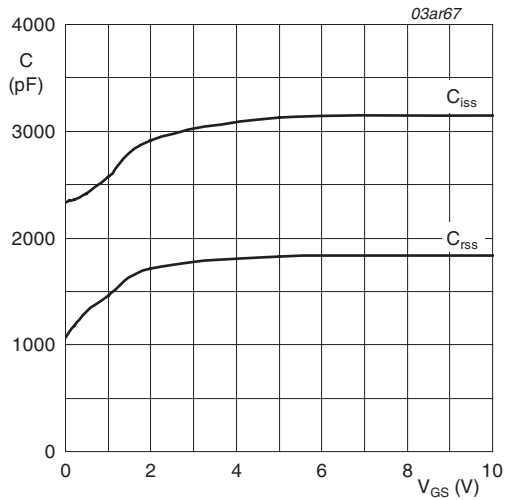
6. Characteristics

Table 6. Characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
Static characteristics						
$V_{(BR)DSS}$	drain-source breakdown voltage	$I_D = 250 \mu A$; $V_{GS} = 0 V$; $T_j = 25^\circ C$	25	-	-	V
		$I_D = 250 \mu A$; $V_{GS} = 0 V$; $T_j = -55^\circ C$	22	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1 mA$; $V_{DS} = V_{GS}$; $T_j = 25^\circ C$; see Figure 8 ; see Figure 9	1	1.5	2	V
		$I_D = 1 mA$; $V_{DS} = V_{GS}$; $T_j = 175^\circ C$; see Figure 8 ; see Figure 9	0.5	-	-	V
		$I_D = 1 mA$; $V_{DS} = V_{GS}$; $T_j = -55^\circ C$; see Figure 8 ; see Figure 9	-	-	2.2	V
I_{DSS}	drain leakage current	$V_{DS} = 25 V$; $V_{GS} = 0 V$; $T_j = 25^\circ C$	-	-	1	μA
		$V_{DS} = 25 V$; $V_{GS} = 0 V$; $T_j = 175^\circ C$	-	-	500	μA
I_{GSS}	gate leakage current	$V_{GS} = 10 V$; $V_{DS} = 0 V$; $T_j = 25^\circ C$	-	0.02	100	nA
		$V_{GS} = -10 V$; $V_{DS} = 0 V$; $T_j = 25^\circ C$	-	0.02	100	nA

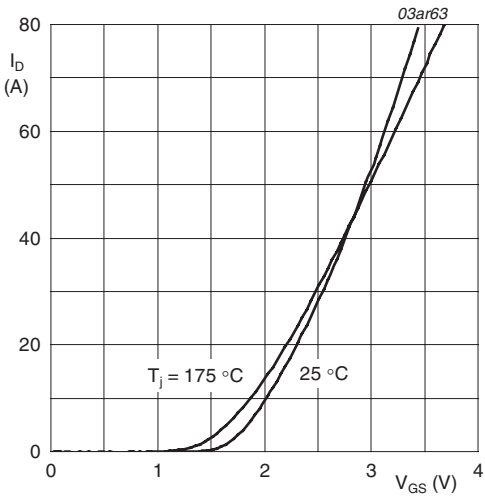
Table 6. Characteristics ...continued

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$R_{DS(on)}$	drain-source on-state resistance	$V_{GS} = 5\text{ V}$; $I_D = 25\text{ A}$; $T_j = 25\text{ }^{\circ}\text{C}$; see Figure 10 ; see Figure 11	-	6.7	7.5	m Ω
		$V_{GS} = 5\text{ V}$; $I_D = 25\text{ A}$; $T_j = 175\text{ }^{\circ}\text{C}$; see Figure 10 ; see Figure 11	-	12.1	13.5	m Ω
		$V_{GS} = 10\text{ V}$; $I_D = 25\text{ A}$; $T_j = 25\text{ }^{\circ}\text{C}$; see Figure 10 ; see Figure 11	-	5.3	6	m Ω
R_G	internal gate resistance (AC)	$f = 1\text{ MHz}$; $T_j = 25\text{ }^{\circ}\text{C}$	-	1.2	-	Ω
Dynamic characteristics						
$Q_{G(tot)}$	total gate charge	$I_D = 25\text{ A}$; $V_{DS} = 12\text{ V}$; $V_{GS} = 4.5\text{ V}$; $T_j = 25\text{ }^{\circ}\text{C}$; see Figure 12 ; see Figure 13	-	16.3	-	nC
		$I_D = 0\text{ A}$; $V_{DS} = 0\text{ V}$; $V_{GS} = 4.5\text{ V}$; $T_j = 25\text{ }^{\circ}\text{C}$	-	12.5	-	nC
Q_{GS}	gate-source charge	$I_D = 25\text{ A}$; $V_{DS} = 12\text{ V}$; $V_{GS} = 4.5\text{ V}$; $T_j = 25\text{ }^{\circ}\text{C}$; see Figure 12 ; see Figure 13	-	4	-	nC
Q_{GS1}	pre-threshold gate-source charge		-	2.5	-	nC
Q_{GS2}	post-threshold gate-source charge		-	1.5	-	nC
Q_{GD}	gate-drain charge		-	5.6	-	nC
$V_{GS(pl)}$	gate-source plateau voltage	$I_D = 25\text{ A}$; $V_{DS} = 12\text{ V}$; $T_j = 25\text{ }^{\circ}\text{C}$; see Figure 12 ; see Figure 13	-	2.4	-	V
C_{iss}	input capacitance	$V_{DS} = 12\text{ V}$; $V_{GS} = 0\text{ V}$; $f = 1\text{ MHz}$; $T_j = 25\text{ }^{\circ}\text{C}$; see Figure 14	-	1375	-	pF
		$V_{DS} = 0\text{ V}$; $V_{GS} = 0\text{ V}$; $f = 1\text{ MHz}$; $T_j = 25\text{ }^{\circ}\text{C}$; see Figure 14	-	2120	-	pF
C_{oss}	output capacitance	$V_{DS} = 12\text{ V}$; $V_{GS} = 0\text{ V}$; $f = 1\text{ MHz}$; $T_j = 25\text{ }^{\circ}\text{C}$; see Figure 14	-	640	-	pF
C_{rss}	reverse transfer capacitance		-	250	-	pF
$t_{d(on)}$	turn-on delay time	$V_{DS} = 12\text{ V}$; $R_L = 0.5\text{ }\Omega$; $V_{GS} = 4.5\text{ V}$; $R_{G(ext)} = 5.6\text{ }\Omega$; $T_j = 25\text{ }^{\circ}\text{C}$	-	15	-	ns
t_r	rise time		-	38	-	ns
$t_{d(off)}$	turn-off delay time		-	32	-	ns
t_f	fall time		-	25	-	ns
Source-drain diode						
V_{SD}	source-drain voltage	$I_S = 25\text{ A}$; $V_{GS} = 0\text{ V}$; $T_j = 25\text{ }^{\circ}\text{C}$; see Figure 15	-	0.86	1.2	V
t_{rr}	reverse recovery time	$I_S = 20\text{ A}$; $dI_S/dt = -100\text{ A}/\mu\text{s}$; $V_{GS} = 0\text{ V}$; $V_{DS} = 25\text{ V}$; $T_j = 25\text{ }^{\circ}\text{C}$	-	34	-	ns
Q_r	recovered charge		-	21	-	nC



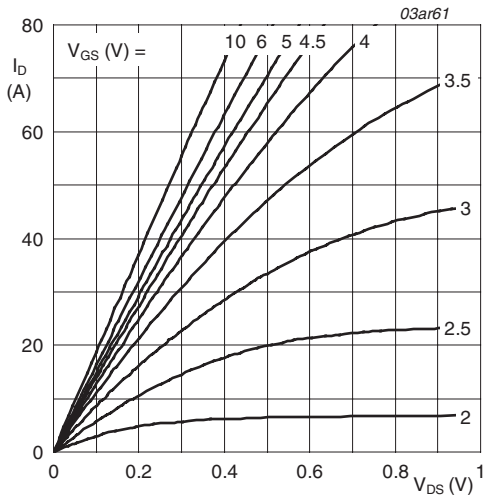
$V_{DS} = 0V$

Fig 5. Input and reverse transfer capacitances as a function of gate-source voltage; typical values



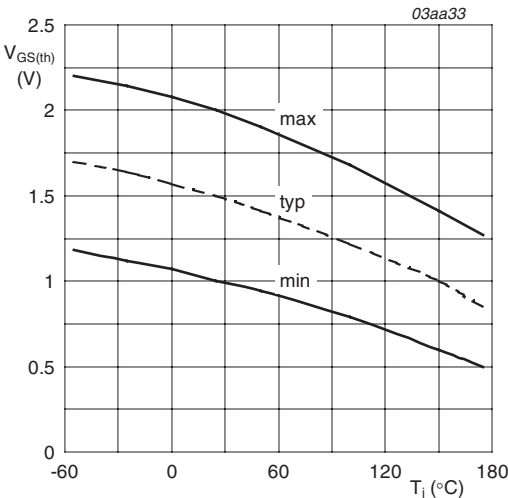
$T_j = 25^\circ C \text{ and } 175^\circ C; V_{DS} > I_D \times R_{DSon}$

Fig 6. Transfer characteristics: drain current as a function of gate-source voltage; typical values



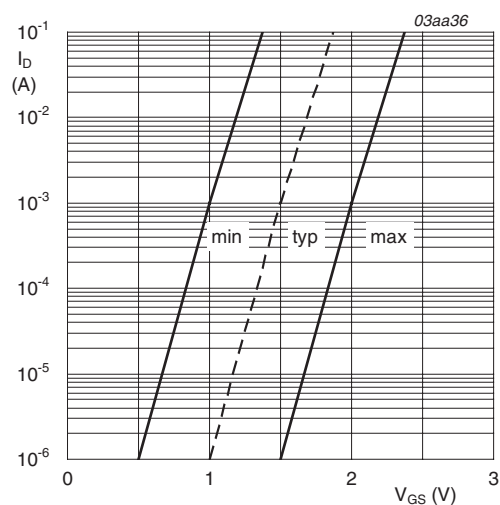
$T_j = 25^\circ C$

Fig 7. Output characteristics: drain current as a function of drain-source voltage; typical values



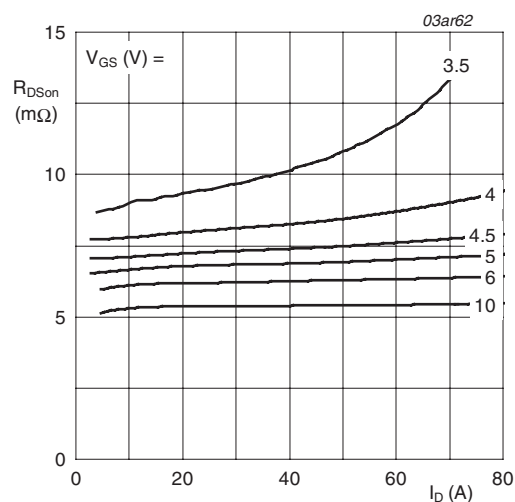
$I_D = 1 mA; V_{DS} = V_{GS}$

Fig 8. Gate-source threshold voltage as a function of junction temperature



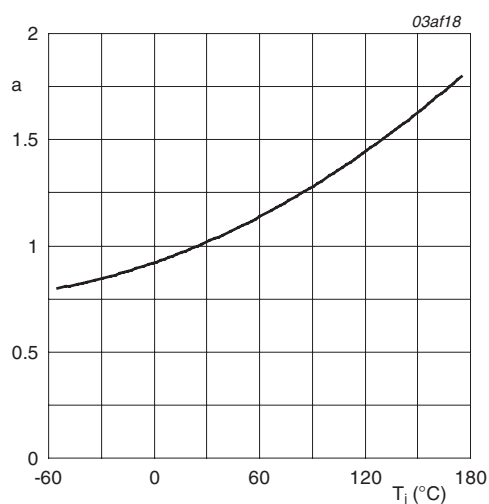
$$T_j = 25^\circ\text{C}; V_{DS} = V_{GS}$$

Fig 9. Sub-threshold drain current as a function of gate-source voltage



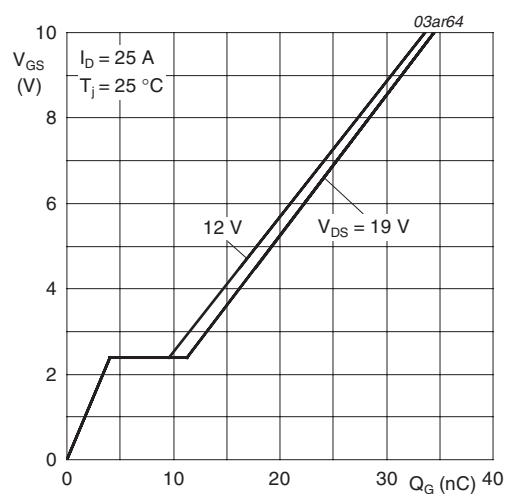
$$T_j = 25^\circ\text{C}$$

Fig 10. Drain-source on-state resistance as a function of drain current; typical values



$$a = \frac{R_{DSon}}{R_{DSon}(25^\circ\text{C})}$$

Fig 11. Normalized drain-source on-state resistance factor as a function of junction temperature



$$I_D = 25\text{A}; V_{DS} = 12\text{V and } 19\text{V}$$

Fig 12. Gate-source voltage as a function of gate charge; typical values

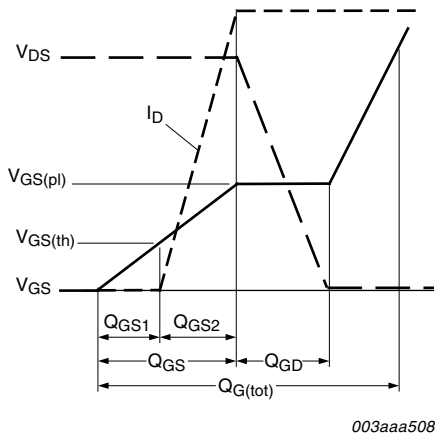


Fig 13. Gate charge waveform definitions

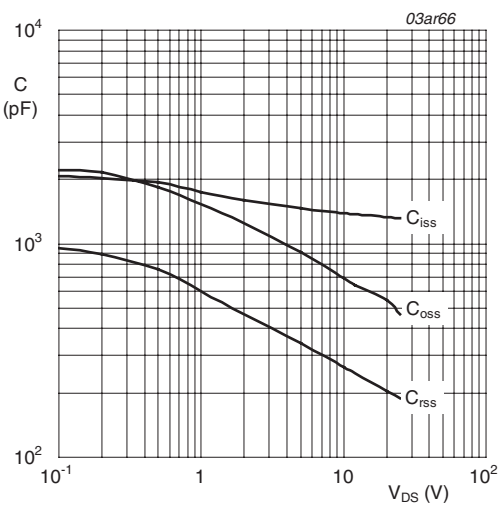


Fig 14. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

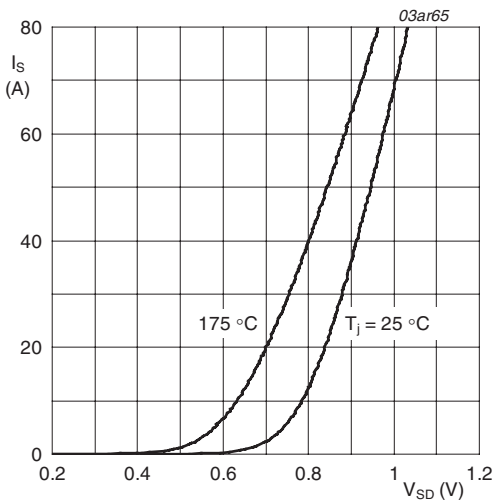


Fig 15. Source current as a function of source-drain voltage; typical values

7. Package outline

Plastic single-ended surface-mounted package (DPAK); 3 leads (one lead cropped) SOT428

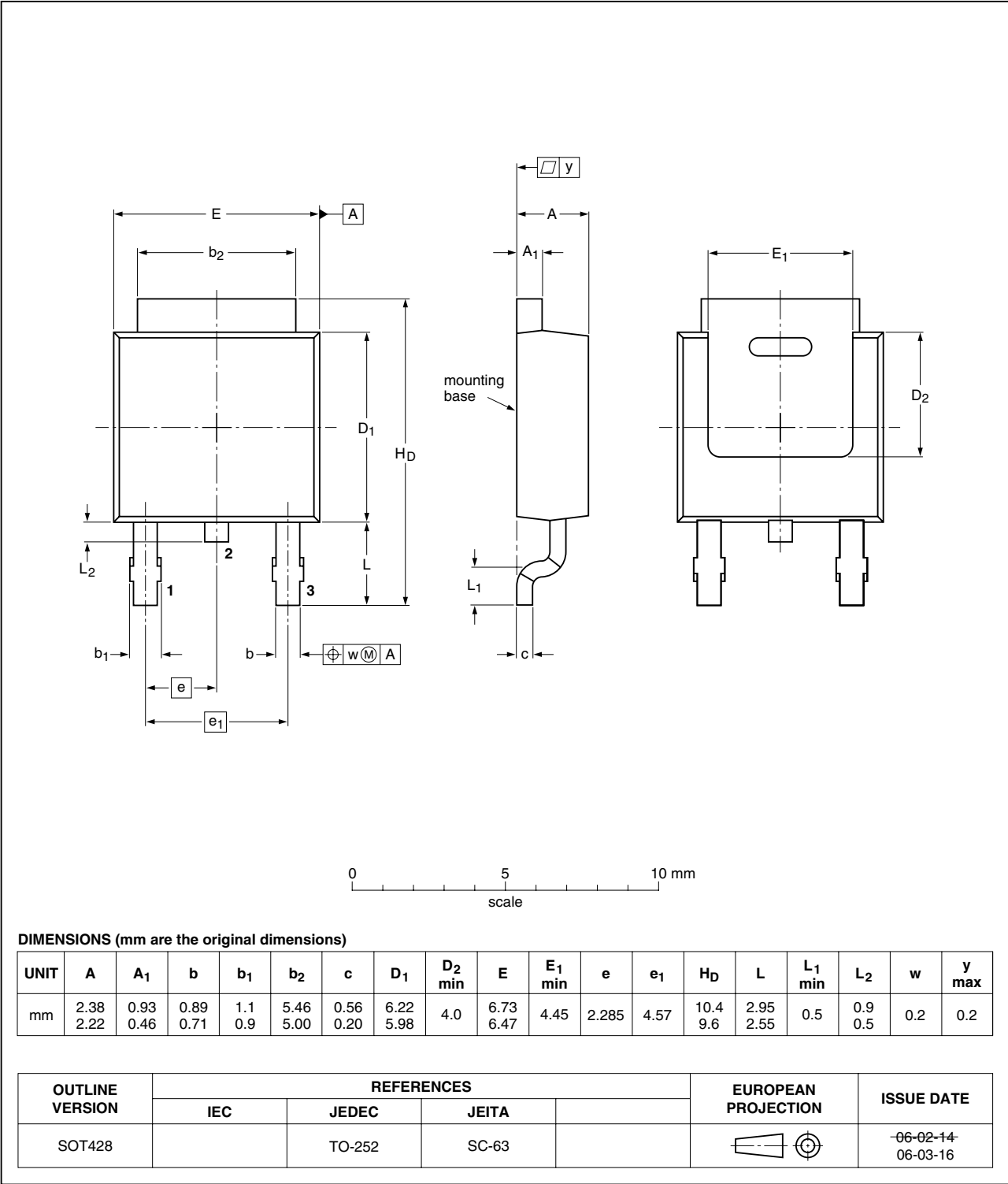


Fig 16. Package outline SOT428 (DPAK)

8. Revision history

Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
PHD108NQ03LT_4	20090605	Product data sheet	-	PHB_PHD_PHU108NQ03LT_3
Modifications:	<ul style="list-style-type: none">• The format of this data sheet has been redesigned to comply with the new identity guidelines of NXP Semiconductors.• Legal texts have been adapted to the new company name where appropriate.• Type number PHD108NQ03LT separated from data sheet PHB_PHD_PHU108NQ03LT_3.			
PHB_PHD_PHU108NQ03LT_3 (9397 750 14707)	20050418	Product data sheet	2004070095	PHP_PHB_PHD108NQ03LT-02
PHP_PHB_PHD108NQ03LT-02 (9397 750 10159)	20020911	Product data	-	PHP_PHB_PHD108NQ03LT-01
PHP_PHB_PHD108NQ03LT-01 (9397 750 09065)	20011218	Product data	-	-

9. Legal information

9.1 Data sheet status

Document status ^{[1][2]}	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

[3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL <http://www.nxp.com>.

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10. Contact information

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